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#### What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Product Status	Obsolete
Core Processor	8051
Core Size	8-Bit
Speed	67MHz
Connectivity	EBI/EMI, I <sup>2</sup> C, LINbus, SPI, UART/USART
Peripherals	CapSense, DMA, POR, PWM, WDT
Number of I/O	25
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x12b; D/A 4x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-BSSOP (0.295", 7.50mm Width)
Supplier Device Package	48-SSOP
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3665pvi-008

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Table 2-2 shows the pinout for the 72-pin CSP package. Since there are four  $V_{DDIO}$  pins, the set of I/O pins associated with any  $V_{DDIO}$  may sink up to 100 mA total, same as for the 100-pin and 68-pin devices.

Table	2-2	COD	Dinout	
Table	2-Z.	COP	Pinout	

Ball	Name	Ball	Name	Ball	Name
G6	P2[5]	F1	VDDD	A5	VDDA
E5	P2[6]	E1	VSSD	A6	VSSD
F5	P2[7]	E2	VCCD	B6	P12[2]
J7	P12[4]	C1	P15[0]	C6	P12[3]
H6	P12[5]	C2	P15[1]	A7	P0[0]
J6	VSSB	D2	P3[0]	B7	P0[1]
J5	Ind	D3	P3[1]	B5	P0[2]
H5	VBOOST	D4	P3[2]	C5	P0[3]
J4	VBAT	D5	P3[3]	A8	VIO0
H4	VSSD	B4	P3[4]	D6	P0[4]
J3	XRES_N	B3	P3[5]	D7	P0[5]
H3	P1[0]	A1	VIO3	C7	P0[6]
G3	P1[1]	B2	P3[6]	C8	P0[7]
H2	P1[2]	A2	P3[7]	E8	VCCD
J2	P1[3]	C3	P12[0]	F8	VSSD
G4	P1[4]	C4	P12[1]	G8	VDDD
G5	P1[5]	E3	P15[2]	E7	P15[4]
J1	VIO1	E4	P15[3]	F7	P15[5]
F4	P1[6]	B1 <sup>[12]</sup>	NC	G7	P2[0]
F3	P1[7]	B8 <sup>[12]</sup>	NC	H7	P2[1]
H1	P12[6]	D1 <sup>[12]</sup>	NC	H8	P2[2]
G1	P12[7]	D8 <sup>[12]</sup>	NC	F6	P2[3]
G2	P15[6]	A3	VCCA	E6	P2[4]
F2	P15[7]	A4	VSSA	J8	VIO2

Figure 2-7 and Figure 2-8 on page 12 show an example schematic and an example PCB layout, for the 100-pin TQFP part, for optimal analog performance on a two-layer board.

- The two pins labeled VDDD must be connected together.
- The two pins labeled Vccd must be connected together, with capacitance added, as shown in Figure 2-7 and Power System on page 31. The trace between the two Vccd pins should be as short as possible.
- The two pins labeled VSSD must be connected together.

For information on circuit board layout issues for mixed signals, refer to the application note AN57821 - Mixed Signal Circuit Board Layout Considerations for PSoC® 3 and PSoC 5.

Notes

<sup>12.</sup> Pins are Do Not Use (DNU) on devices without USB. The pin must be left floating.

<sup>13.</sup> This feature on select devices only. See Ordering Information on page 120 for details.





### Figure 2-7. Example Schematic for 100-pin TQFP Part With Power Connections

**Note** The two Vccd pins must be connected together with as short a trace as possible. A trace under the device is recommended, as shown in Figure 2-8 on page 12.

For more information on pad layout, refer to http://www.cypress.com/cad-resources/psoc-3-cad-libraries.



VCCA. Output of the analog core regulator or the input to the analog core. Requires a 1uF capacitor to VSSA. The regulator output is not designed to drive external circuits. Note that if you use the device with an external core regulator (externally regulated mode), the voltage applied to this pin must not exceed the allowable range of 1.71 V to 1.89 V. When using the internal core regulator, (internally regulated mode, the default), do not tie any power to this pin. For details see Power System on page 31.

VCCD. Output of the digital core regulator or the input to the digital core. The two VCCD pins must be shorted together, with the trace between them as short as possible, and a 1uF capacitor to VSSD. The regulator output is not designed to drive external circuits. Note that if you use the device with an external core regulator (externally regulated mode), the voltage applied to this pin must not exceed the allowable range of 1.71 V to 1.89 V. When using the internal core regulator (internally regulated mode, the default), do not tie any power to this pin. For details see Power System on page 31.

VDDA. Supply for all analog peripherals and analog core regulator. VDDA must be the highest voltage present on the device. All other supply pins must be less than or equal to VDDA.

**VDDD.** Supply for all digital peripherals and digital core regulator. VDDD must be less than or equal to VDDA.

- VSSA. Ground for all analog peripherals.
- **VSSB.** Ground connection for boost pump.
- VSSD. Ground for all digital logic and I/O pins.

**VDDIO0, VDDIO1, VDDIO2, VDDIO3.** Supply for I/O pins. See pinouts for specific I/O pin to VDDIO mapping. Each VDDIO must be tied to a valid operating voltage (1.71 V to 5.5 V), and must be less than or equal to VDDA.

**XRES** (and configurable **XRES**). External reset pin. Active low with internal pull-up. Pin P1[2] may be configured to be a XRES pin; see "Nonvolatile Latches (NVLs)" on page 24.

# 4. CPU

### 4.1 8051 CPU

The CY8C36 devices use a single cycle 8051 CPU, which is fully compatible with the original MCS-51 instruction set. The CY8C36 family uses a pipelined RISC architecture, which executes most instructions in 1 to 2 cycles to provide peak performance of up to 33 MIPS with an average of 2 cycles per instruction. The single cycle 8051 CPU runs ten times faster than a standard 8051 processor.

The 8051 CPU subsystem includes these features:

- Single cycle 8051 CPU
- Up to 64 KB of flash memory, up to 2 KB of EEPROM, and up to 8 KB of SRAM
- 512-byte instruction cache between CPU and flash
- Programmable nested vector interrupt controller
- DMA controller
- Peripheral HUB (PHUB)
- External memory interface (EMIF)



### 6.2.1 Power Modes

PSoC 3 devices have four different power modes, as shown in Table 6-2 and Table 6-3. The power modes allow a design to easily provide required functionality and processing power while simultaneously minimizing power consumption and maximizing battery life in low-power and portable devices.

PSoC 3 power modes, in order of decreasing power consumption are:

- Active
- Alternate Active
- Sleep
- Hibernate

#### Table 6-2. Power Modes

Active is the main processing mode. Its functionality is configurable. Each power controllable subsystem is enabled or disabled by using separate power configuration template registers. In alternate active mode, fewer subsystems are enabled, reducing power. In sleep mode most resources are disabled regardless of the template settings. Sleep mode is optimized to provide timed sleep intervals and RTC functionality. The lowest power mode is hibernate, which retains register and SRAM state, but no clocks, and allows wakeup only from I/O pins. Figure 6-5 illustrates the allowable transitions between power modes. Sleep and hibernate modes should not be entered until all V<sub>DDIO</sub> supplies are at valid voltage levels.

Power Modes	Description	Entry Condition	Wakeup Source	Active Clocks	Regulator
Active	Primary mode of operation, all peripherals available (programmable)	Wakeup, reset, manual register entry	Any interrupt	Any (programmable)	All regulators available. Digital and analog regulators can be disabled if external regulation used.
Alternate Active	Similar to Active mode, and is typically configured to have fewer peripherals active to reduce power. One possible configuration is to use the UDBs for processing, with the CPU turned off	Manual register entry	Any interrupt	Any (programmable)	All regulators available. Digital and analog regulators can be disabled if external regulation used.
Sleep	All subsystems automatically disabled	Manual register entry	Comparator, PICU, I <sup>2</sup> C, RTC, CTW, LVD	ILO/kHzECO	Both digital and analog regulators buzzed. Digital and analog regulators can be disabled if external regulation used.
Hibernate	All subsystems automatically disabled Lowest power consuming mode with all peripherals and internal regulators disabled, except hibernate regulator is enabled Configuration and memory contents retained	Manual register entry	PICU	-	Only hibernate regulator active.

#### Table 6-3. Power Modes Wakeup Time and Power Consumption

Sleep Modes	Wakeup Time	Current (Typ)	Code Execution	Digital Resources	Analog Resources	Clock Sources Available	Wakeup Sources	Reset Sources
Active	-	1.2 mA <sup>[16]</sup>	Yes	All	All	All	-	All
Alternate Active	-	-	User defined	All	All	All	-	All
Sleep	<15 µs	1 µA	No	I <sup>2</sup> C	Comparator	ILO/kHzECO	Comparator, PICU, I <sup>2</sup> C, RTC, CTW, LVD	XRES, LVD, WDR
Hibernate	<100 µs	200 nA	No	None	None	None	PICU	XRES

Note 16. Bus clock off. Execute from cache at 6 MHz. See Table 11-2 on page 72.



### 6.4.1 Drive Modes

Each GPIO and SIO pin is individually configurable into one of the eight drive modes listed in Table 6-3. Three configuration bits are used for each pin (DM[2:0]) and set in the PRTxDM[2:0] registers. Figure 6-12 depicts a simplified pin view based on each of the eight drive modes. Table 6-3 shows the I/O pin's drive state based on the port data register value or digital array signal if bypass mode is selected. Note that the actual I/O pin voltage is determined by a combination of the selected drive mode and the load at the pin. For example, if a GPIO pin is configured for resistive pull-up mode and driven high while the pin is floating, the voltage measured at the pin is a high logic state. If the same GPIO pin is externally tied to ground then the voltage unmeasured at the pin is a low logic state.

#### Figure 6-12. Drive Mode



The 'Out' connection is driven from either the Digital System (when the Digital Output terminal is connected) or the Data Register (when HW connection is disabled). The 'In' connection drives the Pin State register, and the Digital System if the Digital Input terminal is enabled and connected. The 'An' connection connects to the Analog System.

#### Table 6-3. Drive Modes

Diagram	Drive Mode	PRTxDM2	PRTxDM1	PRTxDM0	PRTxDR = 1	PRTxDR = 0
0	High impedance analog	0	0	0	High Z	High Z
1	High impedance digital	0	0	1	High Z	High Z
2	Resistive pull-up <sup>[18]</sup>	0	1	0	Res High (5K)	Strong Low
3	Resistive pull-down <sup>[18]</sup>	0	1	1	Strong High	Res Low (5K)
4	Open drain, drives low	1	0	0	High Z	Strong Low
5	Open drain, drive high	1	0	1	Strong High	High Z
6	Strong drive	1	1	0	Strong High	Strong Low
7	Resistive pull-up and pull-down <sup>[18]</sup>	1	1	1	Res High (5K)	Res Low (5K)





Figure 8-1. Analog Subsystem Block Diagram



The PSoC Creator software program provides a user friendly interface to configure the analog connections between the GPIO and various analog resources and connections from one analog resource to another. PSoC Creator also provides component libraries that allow you to configure the various analog blocks to perform application specific functions (PGA, transimpedance amplifier, voltage DAC, current DAC, and so on). The tool also generates API interface libraries that allow you to write firmware that allows the communication between the analog peripheral and CPU/Memory.

## 8.1 Analog Routing

The CY8C36 family of devices has a flexible analog routing architecture that provides the capability to connect GPIOs and different analog blocks, and also route signals between different analog blocks. One of the strong points of this flexible routing architecture is that it allows dynamic routing of input and output connections to the different analog blocks.

For information on how to make pin selections for optimal analog routing, refer to the application note, AN58304 - PSoC® 3 and PSoC® 5 - Pin Selection for Analog Designs.

#### 8.1.1 Features

- Flexible, configurable analog routing architecture
- 16 analog globals (AG) and two analog mux buses (AMUXBUS) to connect GPIOs and the analog blocks
- Each GPIO is connected to one analog global and one analog mux bus
- Eight analog local buses (abus) to route signals between the different analog blocks
- Multiplexers and switches for input and output selection of the analog blocks

#### 8.1.2 Functional Description

Analog globals (AGs) and analog mux buses (AMUXBUS) provide analog connectivity between GPIOs and the various analog blocks. There are 16 AGs in the CY8C36 family. The analog routing architecture is divided into four quadrants as shown in Figure 8-2. Each quadrant has four analog globals (AGL[0..3], AGL[4..7], AGR[0..3], AGR[4..7]). Each GPIO is connected to the corresponding AG through an analog switch. The analog mux bus is a shared routing resource that connects to every GPIO through an analog switch. There are two AMUXBUS routes in CY8C36, one in the left half (AMUXBUSL) and one in the right half (AMUXBUSR), as shown in Figure 8-2.



### 9.2 Serial Wire Debug Interface

The SWD interface is the preferred alternative to the JTAG interface. It requires only two pins instead of the four or five needed by JTAG. SWD provides all of the programming and debugging features of JTAG at the same speed. SWD does not provide access to scan chains or device chaining. The SWD clock frequency can be up to 1/3 of the CPU clock frequency.

SWD uses two pins, either two of the JTAG pins (TMS and TCK) or the USBIO D+ and D– pins. The USBIO pins are useful for in system programming of USB solutions that would otherwise require a separate programming connector. One pin is used for the data clock and the other is used for data input and output.

SWD can be enabled on only one of the pin pairs at a time. This only happens if, within 8  $\mu$ s (key window) after reset, that pin pair

(JTAG or USB) receives a predetermined acquire sequence of 1s and 0s. If the NVL latches are set for SWD (see Section 5.5), this sequence need not be applied to the JTAG pin pair. The acquire sequence must always be applied to the USB pin pair.

SWD is used for debugging or for programming the flash memory.

The SWD interface can be enabled from the JTAG interface or disabled, allowing its pins to be used as GPIO. Unlike JTAG, the SWD interface can always be reacquired on any device during the key window. It can then be used to reenable the JTAG interface, if desired. When using SWD or JTAG pins as standard GPIO, make sure that the GPIO functionality and PCB circuits do not interfere with SWD or JTAG use.



#### Figure 9-2. SWD Interface Connections between PSoC 3 and Programmer

<sup>1</sup> The voltage levels of the Host Programmer and the PSoC 3 voltage domains involved in Programming should be the same. XRES pin (XRES\_N or P1[2]) is powered by V<sub>DDI01</sub>. The USB SWD pins are powered by V<sub>DDD</sub>. So for Programming using the USB SWD pins with XRES pin, the V<sub>DDD</sub>, V<sub>DDI01</sub> of PSoC 3 should be at the same voltage level as Host V<sub>DD</sub>. Rest of PSoC 3 voltage domains (V<sub>DDA</sub>, V<sub>DDI00</sub>, V<sub>DDI02</sub>, V<sub>DDI03</sub>) need not be at the same voltage level as host Programmer. The Port 1 SWD pins are powered by V<sub>DDI01</sub>. So V<sub>DDI01</sub> of PSoC 3 should be at same voltage level as host Programmer. The Port 1 SWD pins are powered by V<sub>DDI01</sub>. So V<sub>DDI01</sub> of PSoC 3 voltage domains (V<sub>DDA</sub>, V<sub>DDI02</sub>, V<sub>DDI03</sub>) need not be at the same voltage level as host Programming. Rest of PSoC 3 voltage domains (V<sub>DDA</sub>, V<sub>DDI00</sub>, V<sub>DDI02</sub>, V<sub>DDI02</sub>, V<sub>DDI01</sub>. So V<sub>DDI01</sub> of PSoC 3 voltage domains (V<sub>DDA</sub>, V<sub>DDI00</sub>, V<sub>DDI02</sub>, V<sub>DDI03</sub>) need not be at the same voltage level as host Programming. Rest of PSoC 3 voltage domains (V<sub>DDD</sub>, V<sub>DDA</sub>, V<sub>DDI00</sub>, V<sub>DDI02</sub>, V<sub>DDI03</sub>) need not be at the same voltage level as host Programmer.

<sup>2</sup> Vdda must be greater than or equal to all other power supplies (Vddd, Vddio's) in PSoC 3.

- <sup>3</sup> For Power cycle mode Programming, XRES pin is not required. But the Host programmer must have the capability to toggle power (Vddd, Vdda, All Vddio's) to PSoC 3. This may typically require external interface circuitry to toggle power which will depend on the programming setup. The power supplies can be brought up in any sequence, however, once stable, VDDA must be greater than or equal to all other supplies.
- <sup>4</sup> P1[2] will be configured as XRES by default only for 48-pin devices (without dedicated XRES pin). For devices with dedicated XRES pin, P1[2] is GPIO pin by default. So use P1[2] as Reset pin only for 48pin devices, but use dedicated XRES pin for rest of devices.



### 9.8 CSP Package Bootloader

A factory-installed bootloader program is included in all devices with CSP packages. The bootloader is compatible with PSoC Creator 3.0 bootloadable project files and has the following features:

- I<sup>2</sup>C-based
- SCLK and SDAT available at P1[6] and P1[7], respectively
- External pull-up resistors required
- I<sup>2</sup>C slave, address 4, data rate = 100 kbps
- Single application
- Wait two seconds for bootload command
- Other bootloader options are as set by the PSoC Creator 3.0 Bootloader Component default
- Occupies the bottom 9K of flash

For more information on this bootloader, see the following Cypress application notes:

- AN89611 PSoC<sup>®</sup> 3 AND PSoC 5LP Getting Started With Chip Scale Packages (CSP)
- AN73854 PSoC 3 and PSoC 5 LP Introduction to Bootloaders
- AN60317 PSoC 3 and PSoC 5 LP I<sup>2</sup>C Bootloader

Note that a PSOC Creator bootloadable project must be associated with .hex and .elf files for a bootloader project that is configured for the target device. Bootloader .hex and .elf files can be found at www.cypress.com/go/PSoC3datasheet.

The factory-installed bootloader can be overwritten using JTAG or SWD programming.



# 11. Electrical Specifications

Specifications are valid for –40 °C  $\leq$  T<sub>A</sub>  $\leq$  85 °C and T<sub>J</sub>  $\leq$  100 °C, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted. The unique flexibility of the PSoC UDBs and analog blocks enable many functions to be implemented in PSoC Creator components, see the component data sheets for full AC/DC specifications of individual functions. See the "Example Peripherals" section on page 44 for further explanation of PSoC Creator components.

### 11.1 Absolute Maximum Ratings

	Table 11-1.	<b>Absolute Maximum</b>	Ratings DC S	pecifications <sup>[22]</sup>
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Parameter	Description	Conditions	Min	Тур	Max	Units
V <sub>DDA</sub>	Analog supply voltage relative to V <sub>SSA</sub>		-0.5	_	6	V
V <sub>DDD</sub>	Digital supply voltage relative to $V_{SSD}$		-0.5	_	6	V
V <sub>DDIO</sub>	I/O supply voltage relative to $V_{\mbox{SSD}}$		-0.5	-	6	V
V <sub>CCA</sub>	Direct analog core voltage input		-0.5	-	1.95	V
V <sub>CCD</sub>	Direct digital core voltage input		-0.5	-	1.95	V
V <sub>SSA</sub>	Analog ground voltage		V <sub>SSD</sub> – 0.5	_	V <sub>SSD</sub> + 0.5	V
V <sub>GPIO</sub> <sup>[23]</sup>	DC input voltage on GPIO	Includes signals sourced by $V_{\text{DDA}}$ and routed internal to the pin	V <sub>SSD</sub> – 0.5	_	V <sub>DDIO</sub> + 0.5	V
V <sub>SIO</sub>	DC input voltage on SIO	Output disabled	$V_{SSD} - 0.5$	-	7	V
		Output enabled	$V_{SSD} - 0.5$	-	6	V
V <sub>IND</sub>	Voltage at boost converter input		0.5	-	5.5	V
V <sub>BAT</sub>	Boost converter supply		$V_{SSD} - 0.5$	-	5.5	V
I <sub>VDDIO</sub>	Current per V <sub>DDIO</sub> supply pin		-	_	100	mA
I <sub>GPIO</sub>	GPIO current		-30	-	41	mA
I <sub>SIO</sub>	SIO current		-49	-	28	mA
IUSBIO	USBIO current		-56	_	59	mA
V <sub>EXTREF</sub>	ADC external reference inputs	Pins P0[3], P3[2]	-	-	2	V
LU	Latch up current <sup>[24]</sup>		-140	-	140	mA
ESD	Electrostatic discharge voltage,	V <sub>SSA</sub> tied to V <sub>SSD</sub>	2200	-	_	V
	Human body model	$V_{\rm SSA}$ not tied to $V_{\rm SSD}$	750	-	-	V
ESD <sub>CDM</sub>	Electrostatic discharge voltage, Charge device model		500	_	-	V

Notes

22. Usage above the absolute maximum conditions listed in Table 11-1 may cause permanent damage to the device. Exposure to Absolute Maximum conditions for extended periods of time may affect device reliability. The Maximum Storage Temperature is 150 °C in compliance with JEDEC Standard JESD22-A103, High Temperature Storage Life. When used below Absolute Maximum conditions but above normal operating conditions, the device may not operate to specification.
 23. The V<sub>DDIO</sub> supply voltage must be greater than the maximum voltage on the associated GPIO pins. Maximum voltage on GPIO pin ≤ V<sub>DDIO</sub> ≤ V<sub>DDA</sub>.
 24. Meets or exceeds JEDEC Spec EIA/JESD78 IC Latch-up Test.



### **11.2 Device Level Specifications**

Specifications are valid for –40  $^{\circ}C \le T_A \le 85 ~^{\circ}C$  and  $T_J \le 100 ~^{\circ}C$ , except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.2.1 Device Level Specifications

## Table 11-2. DC Specifications

Parameter	Description	Conditions		Min	Typ <sup>[29]</sup>	Max	Units
V <sub>DDA</sub>	Analog supply voltage and input to analog core regulator	Analog core regulato	or enabled	1.8	-	5.5	V
V <sub>DDA</sub>	Analog supply voltage, analog regulator bypassed	Analog core regulato	or disabled	1.71	1.8	1.89	V
V <sub>DDD</sub>	Digital supply voltage relative to $V_{SSD}$	Digital core regulator	enabled	1.8 _	-	V <sub>DDA</sub> <sup>[25]</sup> V <sub>DDA</sub> + 0.1 <sup>[31]</sup>	V
V <sub>DDD</sub>	Digital supply voltage, digital regulator bypassed	Digital core regulator	disabled	1.71	1.8	1.89	V
V <sub>DDIO</sub> <sup>[26]</sup>	I/O supply voltage relative to V <sub>SSIO</sub>			1.71 -	-	V <sub>DDA</sub> <sup>[25]</sup> V <sub>DDA</sub> + 0.1 <sup>[31]</sup>	V
V <sub>CCA</sub>	Direct analog core voltage input (Analog regulator bypass)	Analog core regulato	or disabled	1.71	1.8	1.89	V
V <sub>CCD</sub>	Direct digital core voltage input (Digital regulator bypass)	Digital core regulator	disabled	1.71	1.8	1.89	V
I <sub>DD</sub> <sup>[27, 28]</sup>	Active Mode						
	Only IMO and CPU clock enabled. CPU	$V_{DDX} = 2.7 V - 5.5 V;$	T = -40 °C	-	1.2	2.9	mA
e> bu IM er fiz	executing simple loop from instruction	$F_{CPU} = 6 \text{ MHz}^{130}$	T = 25 °C	-	1.2	3.1	
			T = 85 °C	I	4.9	7.7	
	IMO enabled, bus clock and CPU clock enabled. CPU executing program from flash	V <sub>DDX</sub> = 2.7 V – 5.5 V; F <sub>CPU</sub> = 3 MHz <sup>[30]</sup>	T = -40 °C	I	1.3	2.9	
			T = 25 °C	_	1.6	3.2	
			T = 85 °C	1	4.8	7.5	
		$V_{DDX} = 2.7 V - 5.5 V;$	T = -40 °C	1	2.1	3.7	
		F <sub>CPU</sub> = 6 MHz	T = 25 °C	_	2.3	3.9	1
			T = 85 °C	1	5.6	8.5	
		$V_{DDX} = 2.7 V - 5.5 V;$	T = -40 °C	Ι	3.5	5.2	
		$F_{CPU} = 12 \text{ MHz}^{130}$	T = 25 °C	I	3.8	5.5	
			T = 85 °C	1	7.1	9.8	]
		$V_{DDX} = 2.7 V - 5.5 V;$	T = -40 °C	Ι	6.3	8.1	
		F <sub>CPU</sub> = 24 MHz <sup>[30]</sup>	T = 25 °C	I	6.6	8.3	
			T = 85 °C	Ι	10	13	-
		$V_{DDX} = 2.7 V - 5.5 V;$	T = -40 °C	_	11.5	13.5	
		$F_{CPU} = 48 \text{ MHz}^{130}$	T = 25 °C	-	12	14	
			T = 85 °C	_	15.5	18.5	
		$V_{DDX} = 2.7 V - 5.5 V;$	T = -40 °C	_	16	18	
		F <sub>CPU</sub> = 62 MHz	T = 25 °C	_	16	18	
			T = 85 °C	-	19.5	23	

#### Notes

Notes
25. The power supplies can be brought up in any sequence however once stable V<sub>DDA</sub> must be greater than or equal to all other supplies.
26. The V<sub>DDIO</sub> supply voltage must be greater than the maximum voltage on the associated GPIO pins. Maximum voltage on GPIO pin ≤ V<sub>DDIO</sub> ≤ V<sub>DDA</sub>.
27. Total current for all power domains: digital (l<sub>DDD</sub>), analog (l<sub>DDA</sub>), and I/Os (l<sub>DDIO0, 1, 2, 3</sub>). Boost not included. All I/Os floating.
28. The current consumption of additional peripherals that are implemented only in programmed logic blocks can be found in their respective datasheets, available in PSoC Creator, the integrated design environment. To estimate total current, find the CPU current at the frequency of interest and add peripheral currents for your particular system from the device datasheet and component datasheets.

29. V<sub>DDX</sub> = 3.3 V.

30. Based on device characterization (Not production tested).

31. Guaranteed by design, not production tested.



# Table 11-3. AC Specifications<sup>[37]</sup>

Parameter	Description	Conditions	Min	Тур	Max	Units
F <sub>CPU</sub>	CPU frequency	$1.71~V \le V_{DDD} \le 5.5~V$	DC	-	67.01	MHz
F <sub>BUSCLK</sub>	Bus frequency	$1.71~V \le V_{DDD} \le 5.5~V$	DC	-	67.01	MHz
Svdd	V <sub>DD</sub> ramp rate		_	-	0.066	V/µs
T <sub>IO_INIT</sub>	Time from $V_{DDD}/V_{DDA}/V_{CCD}/V_{CCA} \ge$ IPOR to I/O ports set to their reset states		_	-	10	μs
T <sub>STARTUP</sub>	Time from $V_{DDD}/V_{DDA}/V_{CCD}/V_{CCA} \ge PRES$ to CPU executing code at reset vector	$V_{CCA}/V_{DDA}$ = regulated from $V_{DDA}/V_{DDD}$ , no PLL used, fast IMO boot mode (48 MHz typ.)	-	_	40	μs
		$V_{CCA}/V_{CCD}$ = regulated from $V_{DDA}/V_{DDD}$ , no PLL used, slow IMO boot mode (12 MHz typ.)	_	-	74	μs
T <sub>SLEEP</sub>	Wakeup from sleep mode – Application of non–LVD interrupt to beginning of execution of next CPU instruction		_	-	15	μs
T <sub>HIBERNATE</sub>	Wakeup from hibernate mode – Application of external interrupt to beginning of execution of next CPU instruction		_	_	100	μs

Figure 11-4. F<sub>CPU</sub> vs. V<sub>DD</sub>





Figure 11-24. USBIO Output Rise and Fall Times, GPIO Mode,  $V_{DDD} = 3.3 V$ , 25 pF Load



Table 11-16. USB Driver AC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
Tr	Transition rise time		-	-	20	ns
Tf	Transition fall time		-	-	20	ns
TR	Rise/fall time matching	V <sub>USB_5</sub> , V <sub>USB_3.3</sub> , see USB DC Specifications on page 107	90%	_	111%	
Vcrs	Output signal crossover voltage		1.3	-	2	V



### 11.4.4 XRES

## Table 11-17. XRES DC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
V <sub>IH</sub>	Input voltage high threshold		$0.7 \times V_{DDIO}$	-	-	V
V <sub>IL</sub>	Input voltage low threshold		_	_	0.3 × V <sub>DDIO</sub>	V
Rpullup	Pull-up resistor		3.5	5.6	8.5	kΩ
C <sub>IN</sub>	Input capacitance <sup>[50]</sup>		_	3	_	pF
V <sub>H</sub>	Input voltage hysteresis (Schmitt–Trigger) <sup>[50]</sup>		-	100	-	mV
ldiode	Current through protection diode to $V_{\mbox{DDIO}}$ and $V_{\mbox{SSIO}}$		-	_	100	μA

#### Table 11-18. XRES AC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
T <sub>RESET</sub>	Reset pulse width		1	-	-	μs

### 11.5 Analog Peripherals

Specifications are valid for –40 °C  $\leq$  T<sub>A</sub>  $\leq$  85 °C and T<sub>J</sub>  $\leq$  100 °C, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

### 11.5.1 Opamp

#### Table 11-19. Opamp DC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
V <sub>IOFF</sub>	Input offset voltage		_	_	2	mV
V <sub>OS</sub>	Input offset voltage		-	-	2.5	mV
		Operating temperature –40 °C to 70 °C	-	-	2	mV
TCV <sub>OS</sub>	Input offset voltage drift with temperature	Power mode = high	_	-	±30	µV/°C
Ge1	Gain error, unity gain buffer mode	Rload = 1 kΩ	-	-	±0.1	%
C <sub>IN</sub>	Input capacitance	Routing from pin	_	_	18	pF
V <sub>O</sub>	Output voltage range	1 mA, source or sink, power mode = high	V <sub>SSA</sub> + 0.05	-	V <sub>DDA</sub> – 0.05	V
I <sub>OUT</sub>	Output current capability, source or sink	$V_{SSA}$ + 500 mV $\leq$ Vout $\leq$ V <sub>DDA</sub> -500 mV, V <sub>DDA</sub> > 2.7 V	25	-	-	mA
		$V_{SSA}$ + 500 mV $\leq$ Vout $\leq$ V <sub>DDA</sub> -500 mV, 1.7 V = V <sub>DDA</sub> $\leq$ 2.7 V	16	-	_	mA
I <sub>DD</sub>	Quiescent current	Power mode = min	-	250	400	uA
		Power mode = low	_	250	400	uA
		Power mode = med	-	330	950	uA
		Power mode = high	-	1000	2500	uA
CMRR	Common mode rejection ratio		80	-	-	dB
PSRR	Power supply rejection ratio	$V_{DDA} \ge 2.7 V$	85	-	-	dB
		V <sub>DDA</sub> < 2.7 V	70	-	_	dB
I <sub>IB</sub>	Input bias current <sup>[50]</sup>	25 °C	_	10	_	pА

#### Note

50. Based on device characterization (Not production tested).



Figure 11-25. Opamp Voffset Histogram, 3388 samples/847 parts, 25 °C, V<sub>DDA</sub> = 5 V



Figure 11-27. Opamp Voffset vs Vcommon and  $V_{\text{DDA}},$  25 °C



Figure 11-29. Opamp Operating Current vs  $V_{\mbox{\scriptsize DDA}}$  and Power Mode



Figure 11-26. Opamp Voffset vs Temperature,  $V_{DDA} = 5 V$ 



Figure 11-28. Opamp Output Voltage vs Load Current and Temperature, High Power Mode, 25 °C,  $V_{DDA}$  = 2.7 V





### 11.5.2 Delta-Sigma ADC

Unless otherwise specified, operating conditions are:

- Operation in continuous sample mode
- fclk = 6.144 MHz
- Reference = 1.024 V internal reference bypassed on P3.2 or P0.3
- Unless otherwise specified, all charts and graphs show typical values

#### Table 11-21. 12-bit Delta-sigma ADC DC Specifications

Parameter	Description	Conditions	Min	Тур	Max	Units
	Resolution		8	-	12	bits
	Number of channels, single ended		-	-	No. of GPIO	-
	Number of channels, differential	Differential pair is formed using a pair of GPIOs.	-	-	No. of GPIO/2	-
	Monotonic	Yes	_	-	_	-
Ge	Gain error	Buffered, buffer gain = 1, Range = ±1.024 V, 25 °C	-	-	±0.2	%
Gd	Gain drift	Buffered, buffer gain = 1, Range = ±1.024 V	-	-	50	ppm/°C
Vos	Input offset voltage	Buffered, 12-bit mode	-	-	±0.1	mV
TCVos	Temperature coefficient, input offset voltage	Buffer gain = 1, 12-bit, Range = ±1.024 V	-	-	1	µV/°C
	Input voltage range, single ended <sup>[52]</sup>		V <sub>SSA</sub>	-	V <sub>DDA</sub>	V
	Input voltage range, differential unbuf- fered <sup>[52]</sup>		$V_{SSA}$	-	$V_{DDA}$	V
	Input voltage range, differential, buffered <sup>[52]</sup>		$V_{SSA}$	-	V <sub>DDA</sub> – 1	V
INL12	Integral non linearity <sup>[52]</sup>	Range = ±1.024 V, unbuffered	-	-	±1	LSB
DNL12	Differential non linearity <sup>[52]</sup>	Range = ±1.024 V, unbuffered	-	-	±1	LSB
INL8	Integral non linearity <sup>[52]</sup>	Range = ±1.024 V, unbuffered	_	-	±1	LSB
DNL8	Differential non linearity <sup>[52]</sup>	Range = ±1.024 V, unbuffered	-	-	±1	LSB
Rin_Buff	ADC input resistance	Input buffer used	10	-	I	MΩ
Rin_ADC12	ADC input resistance	Input buffer bypassed, 12 bit, Range = ±1.024 V	-	148 <sup>[53]</sup>	-	kΩ
Rin_ExtRef	ADC external reference input resistance		_	70 <sup>[53, 54]</sup>	-	kΩ
Vextref	ADC external reference input voltage, see also internal reference in Voltage Reference on page 93	Pins P0[3], P3[2]	0.9	_	1.3	V
Current Co	nsumption					
I <sub>DD_12</sub>	$I_{DDA} + I_{DDD}$ current consumption, 12 bit <sup>[52]</sup>	192 ksps, unbuffered	_	-	1.95	mA
I <sub>BUFF</sub>	Buffer current consumption <sup>[52]</sup>		-	-	2.5	mA

Notes

52. Based on device characterization (not production tested).
53. By using switched capacitors at the ADC input an effective input resistance is created. Holding the gain and number of bits constant, the resistance is proportional to the inverse of the clock frequency. This value is calculated, not measured. For more information see the Technical Reference Manual.

54. Recommend an external reference device with an output impedance <100 Ω, for example, the LM185/285/385 family. A 1-μF capacitor is recommended. For more information, see AN61290 - PSoC® 3 and PSoC 5LP Hardware Design Considerations.



# **12. Ordering Information**

In addition to the features listed in Table 12-1, every CY8C36 device includes: a precision on-chip voltage reference, precision oscillators, flash, ECC, DMA, a fixed function I<sup>2</sup>C, 4 KB trace RAM, JTAG/SWD programming and debug, external memory interface, and more. In addition to these features, the flexible UDBs and analog subsection support a wide range of peripherals. To assist you in selecting the ideal part, PSoC Creator makes a part recommendation after you choose the components required by your application. All CY8C36 derivatives incorporate device and flash security in user-selectable security levels; see the TRM for details.

	N	NCU	Co	re			Ana	alog	l					Dig	jital			I/O <sup>L</sup>	ooj			
Part Number	CPU Speed (MHz)	Flash (KB)	SRAM (KB)	EEPROM (KB)	LCD Segment Drive	ADC	DAC	Comparator	SC/CT Analog Blocks <sup>[86]</sup>	Opamps	DFB	CapSense	UDBs <sup>[87]</sup>	16-bit Timer/PWM	FS USB	CAN 2.0b	Total I/O	GPIO	SIO	USBIO	Package	JTAG ID <sup>[89]</sup>
32 KB Flash																						
CY8C3665PVI-008	67	32	4	1	V	12-bit Del-Sig	4	4	4	2	~	r	20	4	-	-	29	25	4	0	48-pin SSOP	0×1E008069
CY8C3665AXI-198	67	32	8	1	۲	12-bit Del-Sig	2	0	0	0	Ι	~	16	0	Ι	Ι	70	62	8	0	100-pin TQFP	0x1E0C6069
CY8C3665LTI-044	67	32	4	1	۲	12-bit Del-Sig	4	4	4	0	<	~	20	4	2	Ι	48	38	8	2	68-pin QFN	0x1E02C069
CY8C3665LTI-199	67	32	8	1	٢	12-bit Del-Sig	2	0	0	0	Ι	~	16	0	Ι	Ι	46	38	8	0	68-pin QFN	0x1E0C7069
CY8C3665FNI-211	67	32	4	1	5	12-bit Del-Sig	4	4	4	4	~	2	20	4	~	-	48	38	8	2	72 WLCSP	0x1E0D3069
64 KB Flash																						
CY8C3666AXI-052	67	64	8	2	5	12-bit Del-Sig	4	4	4	4	~	5	24	4	-	-	70	62	8	0	100-pin TQFP	0×1E034069
CY8C3666AXI-036	67	64	8	2	5	12-bit Del-Sig	4	4	4	4	٨	٢	24	4	~	Ι	72	62	8	2	100-pin TQFP	0×1E024069
CY8C3666LTI-027	67	64	8	2	5	12-bit Del-Sig	4	4	4	4	۲	5	24	4	~		48	38	8	2	68-pin QFN	0×1E01B069
CY8C3666LTI-050	67	64	8	2	٢	12-bit Del-Sig	4	4	4	2	٨	1	24	4	~	-	31	25	4	2	48-pin QFN	0×1E032069
CY8C3666AXI-037	67	64	8	2	۲	12-bit Del-Sig	4	4	4	4	<	~	24	4	Ι	2	70	62	8	0	100-pin TQFP	0×1E025069
CY8C3666AXI-200	67	64	8	2	٢	12-bit Del-Sig	2	2	0	2	Ι	~	20	2	Ι	Ι	70	62	8	0	100-pin TQFP	0x1E0C8069
CY8C3666LTI-201	67	64	8	2	5	12-bit Del-Sig	2	2	0	2	-	2	20	2	-	-	46	38	8	0	68-pin QFN	0x1E0C9069
CY8C3666AXI-202	67	64	8	2	~	12-bit Del-Sig	4	2	2	2	-	~	24	4	-	-	70	62	8	0	100-pin TQFP	0x1E0CA069
CY8C3666LTI-203	67	64	8	2	~	12-bit Del-Sig	4	2	2	2	-	~	24	4	-	-	46	38	8	0	68-pin QFN	0x1E0CB069

Table 12-1. CY8C36 Family with Single Cycle 8051

Notes

86. Analog blocks support a wide variety of functionality including TIA, PGA, and mixers. See the Example Peripherals on page 44 for more information on how analog blocks can be used.

87. UDBs support a wide variety of functionality including SPI, LIN, UART, timer, counter, PWM, PRS, and others. Individual functions may use a fraction of a UDB or multiple UDBs. Multiple functions can share a single UDB. See the Example Peripherals on page 44 for more information on how UDBs can be used.
 88. The I/O Count includes all types of digital I/O: GPIO, SIO, and the two USB I/O. See the I/O System and Routing on page 37 for details on the functionality of each of these types of I/O.

89. The JTAG ID has three major fields. The most significant nibble (left digit) is the version, followed by a 2 byte part number and a 3 nibble manufacturer ID.



# 13. Packaging

## Table 13-1. Package Characteristics

Parameter	Description	Conditions	Min	Тур	Max	Units
T <sub>A</sub>	Operating ambient temperature		-40	25.00	85	°C
TJ	Operating junction temperature		-40	-	100	°C
T <sub>JA</sub>	Package $\theta_{JA}$ (48-pin SSOP)		-	49	-	°C/Watt
T <sub>JA</sub>	Package $\theta_{JA}$ (48-pin QFN)		-	14	-	°C/Watt
T <sub>JA</sub>	Package $\theta_{JA}$ (68-pin QFN)		-	15	-	°C/Watt
T <sub>JA</sub>	Package $\theta_{JA}$ (100-pin TQFP)		-	34	-	°C/Watt
T <sub>JC</sub>	Package $\theta_{JC}$ (48-pin SSOP)		-	24	-	°C/Watt
T <sub>JC</sub>	Package $\theta_{JC}$ (48-pin QFN)		-	15	-	°C/Watt
T <sub>JC</sub>	Package $\theta_{JC}$ (68-pin QFN)		-	13	-	°C/Watt
T <sub>JC</sub>	Package $\theta_{JC}$ (100-pin TQFP)		-	10	-	°C/Watt
T <sub>JA</sub>	Package $\theta_{JA}$ (72-pin CSP)		-	18	-	°C/Watt
T <sub>JC</sub>	Package $\theta_{JC}$ (72-pin CSP)		_	0.13	_	°C/Watt

## Table 13-2. Solder Reflow Peak Temperature

Package	Maximum Peak Temperature	Maximum Time at Peak Temperature
48-pin SSOP	260 °C	30 seconds
48-pin QFN	260 °C	30 seconds
68-pin QFN	260 °C	30 seconds
100-pin TQFP	260 °C	30 seconds
72-pin CSP	260 °C	30 seconds

### Table 13-3. Package Moisture Sensitivity Level (MSL), IPC/JEDEC J-STD-2

Package	MSL
48-pin SSOP	MSL 3
48-pin QFN	MSL 3
68-pin QFN	MSL 3
100-pin TQFP	MSL 3
72-pin CSP	MSL 1



Acronym	Description
PHUB	peripheral hub
PHY	physical layer
PICU	port interrupt control unit
PLA	programmable logic array
PLD	programmable logic device, see also PAL
PLL	phase-locked loop
PMDD	package material declaration data sheet
POR	power-on reset
PRES	precise low-voltage reset
PRS	pseudo random sequence
PS	port read data register
PSoC <sup>®</sup>	Programmable System-on-Chip™
PSRR	power supply rejection ratio
PWM	pulse-width modulator
RAM	random-access memory
RISC	reduced-instruction-set computing
RMS	root-mean-square
RTC	real-time clock
RTL	register transfer language
RTR	remote transmission request
RX	receive
SAR	successive approximation register
SC/CT	switched capacitor/continuous time
SCL	I <sup>2</sup> C serial clock
SDA	I <sup>2</sup> C serial data
S/H	sample and hold
SINAD	signal to noise and distortion ratio
SIO	special input/output, GPIO with advanced features. See GPIO.
SOC	start of conversion

### Table 14-1. Acronyms Used in this Document (continued)

#### Table 14-1. Acronyms Used in this Document (continued)

Acronym	Description
SOF	start of frame
SPI	Serial Peripheral Interface, a communications protocol
SR	slew rate
SRAM	static random access memory
SRES	software reset
SWD	serial wire debug, a test protocol
SWV	single-wire viewer
TD	transaction descriptor, see also DMA
THD	total harmonic distortion
TIA	transimpedance amplifier
TRM	technical reference manual
TTL	transistor-transistor logic
TX	transmit
UART	Universal Asynchronous Transmitter Receiver, a communications protocol
UDB	universal digital block
USB	Universal Serial Bus
USBIO	USB input/output, PSoC pins used to connect to a USB port
VDAC	voltage DAC, see also DAC, IDAC
WDT	watchdog timer
WOL	write once latch, see also NVL
WRES	watchdog timer reset
XRES	external reset I/O pin
XTAL	crystal

# **15. Reference Documents**

PSoC® 3, PSoC® 5 Architecture TRM PSoC® 3 Registers TRM



# **16. Document Conventions**

### 16.1 Units of Measure

### Table 16-1. Units of Measure

Symbol	Unit of Measure
°C	degrees Celsius
dB	decibels
fF	femtofarads
Hz	hertz
KB	1024 bytes
kbps	kilobits per second
Khr	kilohours
kHz	kilohertz
kΩ	kilohms
ksps	kilosamples per second
LSB	least significant bit
Mbps	megabits per second
MHz	megahertz
MΩ	megaohms
Msps	megasamples per second
μA	microamperes
μF	microfarads
μH	microhenrys

Symbol	Unit of Measure
μs	microseconds
μV	microvolts
μW	microwatts
mA	milliamperes
ms	milliseconds
mV	millivolts
nA	nanoamperes
ns	nanoseconds
nV	nanovolts
Ω	ohms
pF	picofarads
ppm	parts per million
ps	picoseconds
S	seconds
sps	samples per second
sqrtHz	square root of hertz
V	volts

#### Table 16-1. Units of Measure (continued)



Description Document	on Title: PS t Number: (	oC <sup>®</sup> 3: CY8C3 01-53413	6 Family Da	tasheet Programmable System-on-Chip (PSoC <sup>®</sup> ) (continued)
Revision	ECN	Submission Date	Orig. of Change	Description of Change
*D	ECN 2903576	Date 04/01/10	<u>Change</u> MKEA	Updated Vb pin in PCB Schematic Updated Tstartup parameter in AC Specifications table Added Load regulation and Line regulation parameters to Inductive Boost Regulator DC Specifications table Updated I <sub>QC</sub> parameter in LCD Direct Drive DC Specs table Updated I <sub>QC</sub> parameter in LCD Direct Drive DC Specs table Updated I <sub>QC</sub> parameter in LCD Direct Drive DC Specs table Updated I <sub>QLT</sub> parameter in LCD Direct Drive DC Specs table Updated I <sub>QLT</sub> parameter in LCD Direct Drive DC Specs table Updated I <sub>QLT</sub> parameter in LCD Direct Drive DC Specs table Added bullets on CapSense in page 1; added CapSense column in Section 12 Removed some references to footnote [1] Changed INC_Rn cycles from 3 to 2 (Table 4-1) Added footnote in PLL AC Specification table Added UDBs subsection under 11.6 Digital Peripherals Updated Figure 2-6 (PCB Layout) Updated Pin Descriptions section and modified Figures 6-6, 6-8, 6-9 Updated LVD in Tables 6-2 and 6-3; modified Low-power modes bullet in page 1 Added note to Figures 2-5 and 6-2; Updated Figure 6-2 to add capacitors for V <sub>DDA</sub> and V <sub>DDD</sub> pins. Changed V <sub>REF</sub> from 0.9 to 0.1% Updated boost converter section (6.2.2) Updated DR rows from Table 11-68. Updated 6.3.1.1, Power Voltage Level Monitors. Updated V <sub>REF</sub> specs in Table 11-20 correct suggestion of execution from flash. Updated V <sub>REF</sub> specs in Table 11-21. Updated Delay from Interrupt signal input to ISR code execution from ISR code in Table11-72. Removed other line in table. Added sentenc to last paragraph of section 6.1.1.3. Updated T <sub>RESP</sub> , high and low-power modes, in Table 11-24. Updated TR condition in Table 11-20. Corrected unit of measurement in Table 11-21. Updated SNR condition in Table 11-20. Corrected unit of measurement in Table 11-21. Updated SNR condition in Table 11-20. Corrected unit of measurement in Table 11-21. Changed POR_TR to PRES_TR). Added sentence saying that LVD circuits can generate a reset to Section 6.3.1.1. Changed POR_TR to PRES_TR). Added sentence saying that LVD circuits can generate a reset to Section
				Added row to Table 11-69. Added brown out note to Section 11.8.1.